

Q.raxx XE A109

Analog Output Module with Digital I/Os

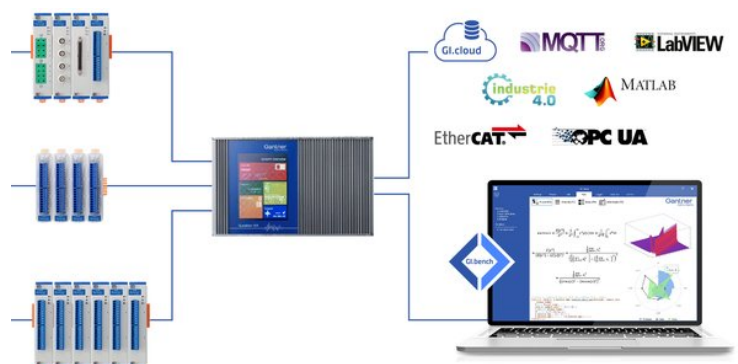
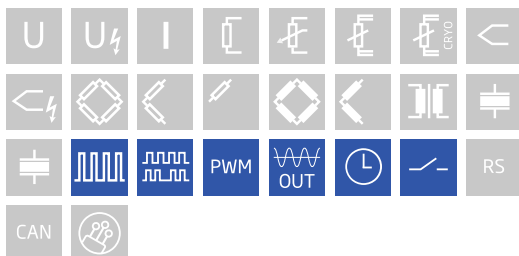
Q.raxx XE is an new addition to the Q.series product family - the ideal 19" rackmount EtherCAT DAQ solution for applications that require high channel density and custom sensor terminations. Q.raxx XE DAQ systems can consist of an integrated EtherCAT bus coupler for communication and 10 measurement modules capable of up to 100 kHz sampling per channel with short cycle times and low jitter for accurate synchronization

- According 19"-standard IEC
- Electromagnetic Compatibility according to EN61000-4 and EN55011
- High density and flexibility with 13 modules in one system in any constellation
- FoE (file access over EtherCAT, ETG.1000.5) and CoE (CAN over EtherCAT, ETG.50001.1)



Key Features

- 4 Analog output channels
voltage (± 10 VDC) or current (0 - 20 mA), configurable per channel
- DAC-resolution 16 bit
100 kHz each channel
- Outputs freely scalable
- 4 digital inputs and outputs
configurable as 2 counter, 2 frequency, or 2 PWM inputs, 4 frequency out, 4 PWM output or 4 state out
- Frequency measurement
Frequency measurement up to 1 MHz, direction detection
- Counter
Forward-backward counter, quadrature counter with reference position recognition (reset/enable), up to 1 MHz
- PWM input
Measurement of duty cycle and frequency
- 3-Way galvanic isolation
500 VDC channel to channel, channel to power supply, and bank



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Technical Data

Analog Output

Channels	4
Accuracy	0.02 % typical
Output type	voltage or current, configurable per channel
Isolation voltage	500 VDC channel to channel to power supply channel to bus ¹

¹ noise pulses up to 1000 VDC, continuous up to 250 VDC

Output Mode Voltage

Output voltage	±10 VDC	
Allowable load resistance	>2 kΩ	
Long-term drift	<1 mV / 24 hrs	<2.5 mV / 8000 hrs
Temperature influence	<2 mV / 10 K Offset drift	<0.05 % / 10 K Gain drift
Noise voltage	<10 mV at 1000 Hz	<2 mV at 10 Hz

Current Output

Output current	0 - 20 mA	
Load burden	<400 Ω	
burden influence	<0.1 μA / Ω	
Long-term stability	<2 μA / 24 hrs	<5 μA / 8000 hrs
Temperature drift	<4 μA / 10 K Offset drift	<0.05 % / 10 K Gain drift
Noise current	<20 μA at 1000 Hz	<4 μA at 10 Hz

Digital Input

Channels	4
Logic levels	TTL or 24 VDC according to IEC 61131-2, Type 1
TTL logic voltage	< 0.8 VDC (Low) > 3 VDC (High)
24 VDC logic voltage	-3 to 5 VDC (Low) 11 to 30 VDC (High)
Input type	PNP (current sinking)
Input voltage	30 VDC max.
Input current	2 mA max.
Isolation voltage	500 VDC, group to group, group to power supply, channel to bus ¹

¹ noise pulses up to 1000 VDC, continuous up to 250 VDC

Digital Input Modes

Status	
Response time	10 µs
Frequency measurement	
Method	Chronos method (optimized by a combination of time measurement and pulse counting), detection of rotational direction (0 deg. / 90 deg.)
Frequency range	0.1 Hz to 1 MHz
Time base	0.001 s to 1 s
Internal reference frequency	48 MHz
Accuracy	0.01% at timebase > 1ms
Resolution	21 ns
Pulse counting	
Accuracy	0.01% at timebase > 1ms
Resolution	21 ns
Counter frequency	1 MHz
Mode(s) of operation	<ul style="list-style-type: none"> - Forward and reverse counting (additional input for direction of counting) - Quadrature counter (additional input for detection of rotational direction) - Quadrature counter with zero reference and reset/enable (two additional inputs)
Pulse-width measurement	
Input frequency	0.1 Hz to 1 MHz
Accuracy	0.01% at timebase > 1ms
Resolution	21 ns

Digital Output

Channels	4
Contact	open drain p-channel MOSFET
Output voltage	12 to 30 VDC (external supply required)
Load capacity	30 VDC / 500 mA (ohmic load)
Isolation voltage	500 VDC, group to group, group to power supply, channel to bus ¹

¹ noise pulses up to 1000 VDC, continuous up to 250 VDC

Digital Output Modes

Status				
	Response time	10 μs (>0.5 A)	100 μs (>0.1 A)	1000 μs (<0.1 A)
Frequency output				
	Frequency range	0.1 Hz to 1 kHz / 10 kHz (depending on load capacity)		
	Accuracy	0.1 %		
	Resolution	1 μs		
PWM output				
	Frequency range	0.1 Hz to 1 kHz / 10 kHz (depending on load capacity)		
	Accuracy	0.1 %		
	Resolution	1 μs		

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Digital to Analog Conversion

Resolution	16-bit
Update rate	100 kHz per channel
Settling time	3 μ s

Communication Interface EtherCAT

Electrical standard	RS-485, 2-wire
Protocols	EtherCAT (LVDS)

Input Power

Input voltage	10 to 30 VDC, overvoltage and overcurrent protection
Power consumption	2 W (approx.)
Input voltage influence	<0.001 % / V

Environmental Specifications

Electromagnetic compatibility	according to IEC 61000-4 and EN 55011
Operating temperature	-20°C to +60°C
Storage temperature	-40°C to +85°C
Relative humidity	5 - 95 % at 50°C (non-condensing)

Remarks

Validity of all listed specifications are subject to a warm-up period of at least 45 minutes

Specifications subject to change without notice

Mechanical information

Material	Aluminum
Measurements (W x H x D)	30x 128 x 120mm
Weight	approx. 200 g

Ordering Information

Article number	511924
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